

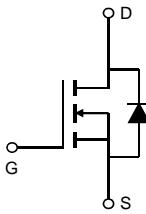


SHENZHEN TUOFENG SEMICONDUCTOR TECHNOLOGY CO.,LTD

PDFN 3333 Plastic-Encapsulate MOSFETS

TF075N03M

N-Channel Enhancement Mode Power MOSFET

Features <ul style="list-style-type: none">• 30V/30A$R_{DS(ON)} = 7.5\text{m}\Omega(\text{Typ.}) @ V_{GS} = 10V$$R_{DS(ON)} = 9.3\text{m}\Omega(\text{Typ.}) @ V_{GS} = 4.5V$• Super High Dense Cell Design• Fast Switching Speed• Low gate Charge• 100% avalanche tested• Lead Free and Green Devices Available Applications <ul style="list-style-type: none">• Switching Application Systems	 <p>PDFN 3333 top view</p>  <p>Schematic diagram</p>
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Absolute Maximum Ratings

Symbol	Parameter	Rating	Unit
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Common Ratings ($T_C = 25^\circ\text{C}$ Unless Otherwise Noted)

V_{DSS}	Drain-Source Voltage	30	V
V_{GSS}	Gate-Source Voltage	± 20	
T_J	Maximum Junction Temperature	150	$^\circ\text{C}$
T_{STG}	Storage Temperature Range	-55 to 150	$^\circ\text{C}$
I_S	Diode Continuous Forward Current	$T_C = 25^\circ\text{C}$	30
			A

Mounted on Large Heat Sink

$I_{DP}^{①}$	300 μs Pulse Drain Current Tested	$T_C = 25^\circ\text{C}$	100	A
$I_D^{②}$	Continuous Drain Current@ $T_C(V_{GS}=10V)$	$T_C = 25^\circ\text{C}$	30	A
	Continuous Drain Current@ $T_A(V_{GS}=10V)^{③}$	$T_A = 25^\circ\text{C}$	9.8	
P_D	Maximum Power Dissipation@ T_C	$T_C = 25^\circ\text{C}$	30	W
	Maximum Power Dissipation@ T_A ^③	$T_A = 25^\circ\text{C}$	3.8	

Notes:

- ①Pulse width limited by safe operating area.
- ②Calculated continuous current based on maximum allowable junction temperature.
- ③When mounted on 1 inch square copper board, $t \leq 10\text{sec}$.
- ④Limited by T_{Jmax} , $I_{AS} = 13\text{A}$, $V_{DD} = 24\text{V}$, $R_G = 50\Omega$, Starting $T_J = 25^\circ\text{C}$.
- ⑤Pulse test; Pulse width $\leq 300\mu\text{s}$, duty cycle $\leq 2\%$.
- ⑥Guaranteed by design, not subject to production testing.



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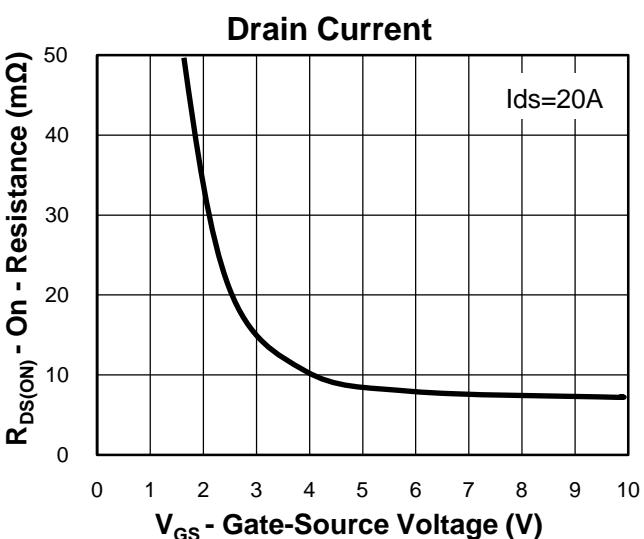
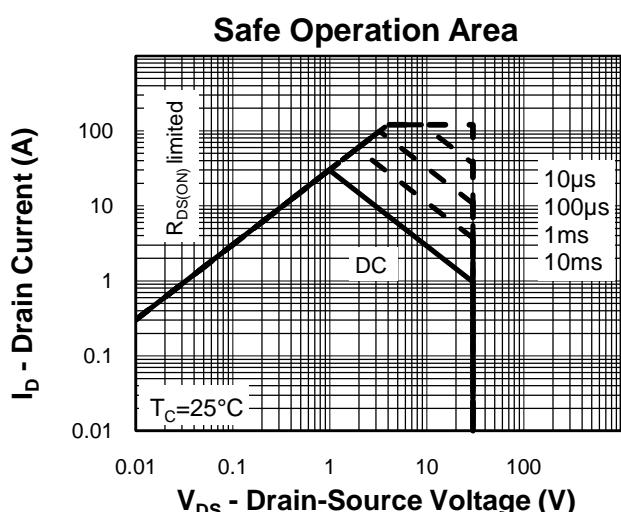
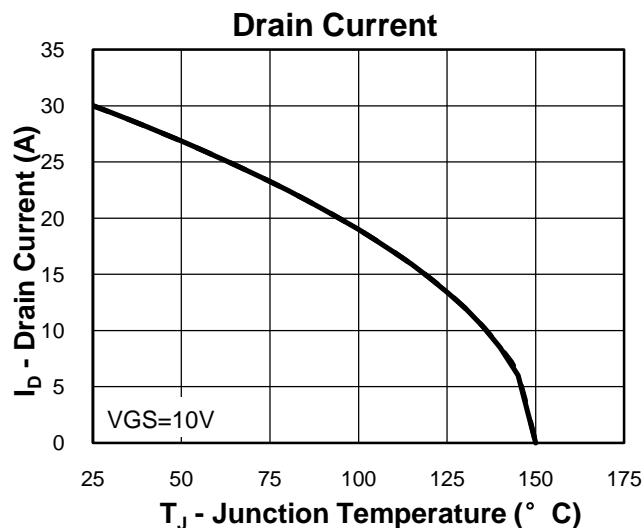
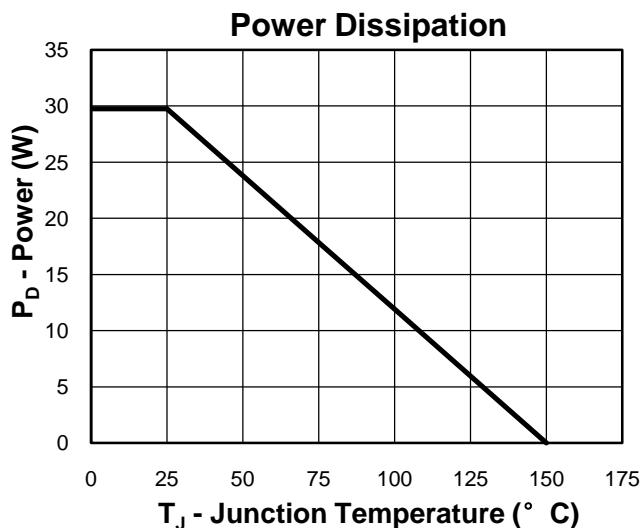
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Symbol	Parameter	Rating	Unit
$R_{\theta JC}$	Thermal Resistance-Junction to Case	4.5	°C/W
$R_{\theta JA}^{(3)}$	Thermal Resistance-Junction to Ambient	37	°C/W
Drain-Source Avalanche Ratings			
$E_{AS}^{(4)}$	Avalanche Energy, Single Pulsed	30	mJ

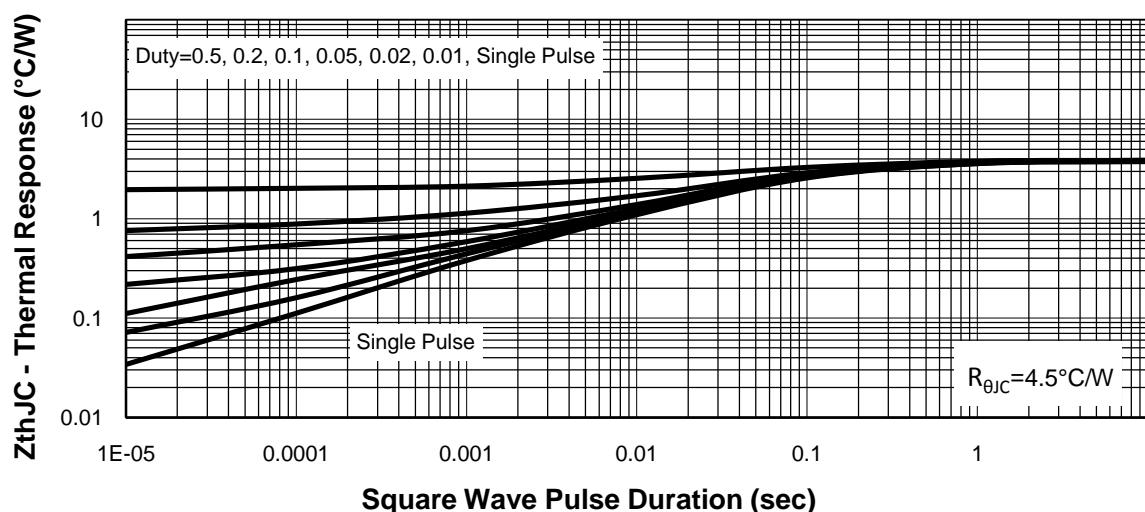
Electrical Characteristics ($T_C=25^\circ C$ Unless Otherwise Noted)

Symbol	Parameter	Test Condition	Min.	Typ.	Max.	Unit
Static Characteristics						
BV_{DSS}	Drain-Source Breakdown Voltage	$V_{GS}=0V, I_{DS}=250\mu A$	30			V
I_{DSS}	Zero Gate Voltage Drain Current	$V_{DS}=30V, V_{GS}=0V$			1	μA
		$T_J=125^\circ C$			30	
$V_{GS(th)}$	Gate Threshold Voltage	$V_{DS}=V_{GS}, I_{DS}=250\mu A$	1.2	1.4	2.2	V
I_{GSS}	Gate Leakage Current	$V_{GS}=\pm 20V, V_{DS}=0V$			± 100	nA
$R_{DS(ON)}^{(5)}$	Drain-Source On-state Resistance	$V_{GS}=10V, I_{DS}=20A$		7.5	9.0	$m\Omega$
		$V_{GS}=4.5V, I_{DS}=15A$		9.3	12	$m\Omega$
Diode Characteristics						
$V_{SD}^{(5)}$	Diode Forward Voltage	$I_{SD}=20A, V_{GS}=0V$			1.2	V
t_{rr}	Reverse Recovery Time	$I_{SD}=20A, dI_{SD}/dt=100A/\mu s$		13		ns
Q_{rr}	Reverse Recovery Charge			8		nC
Dynamic Characteristics ⁽⁶⁾						
R_G	Gate Resistance	$V_{GS}=0V, V_{DS}=0V, F=1MHz$		1		Ω
C_{iss}	Input Capacitance	$V_{GS}=0V, V_{DS}=15V, Frequency=1.0MHz$		1007		pF
C_{oss}	Output Capacitance			128		
C_{rss}	Reverse Transfer Capacitance			117		
$t_{d(ON)}$	Turn-on Delay Time	$V_{DD}=15V, R_L=0.75\Omega, I_{DS}=20A, V_{GEN}=10V, R_G=3\Omega$		5.7		ns
t_r	Turn-on Rise Time			47		
$t_{d(OFF)}$	Turn-off Delay Time			31		
t_f	Turn-off Fall Time			23		
Gate Charge Characteristics ⁽⁶⁾						
Q_g	Total Gate Charge	$V_{DS}=15V, V_{GS}=10V, I_{DS}=20A$		23		nC
Q_{gs}	Gate-Source Charge			4.2		
Q_{gd}	Gate-Drain Charge			4.3		

Typical Characteristics



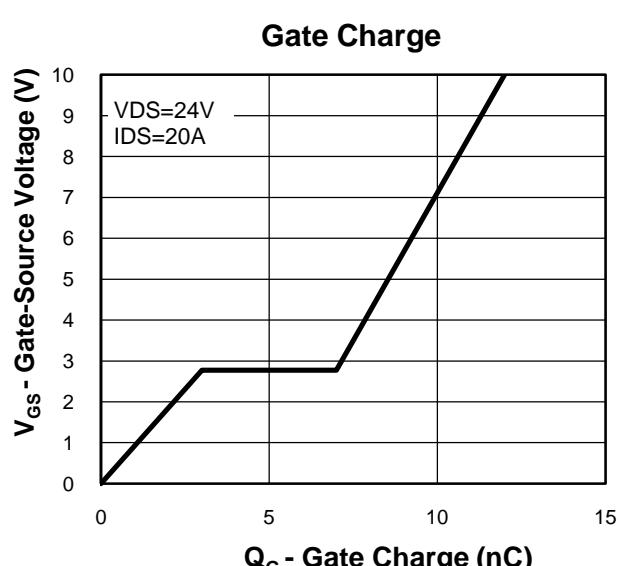
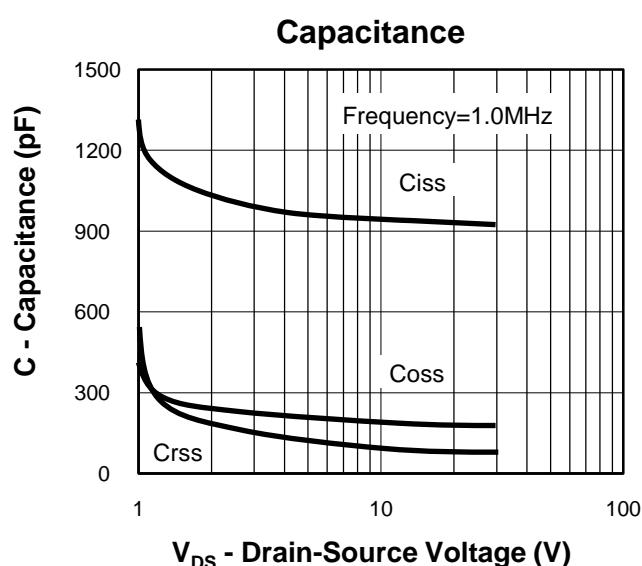
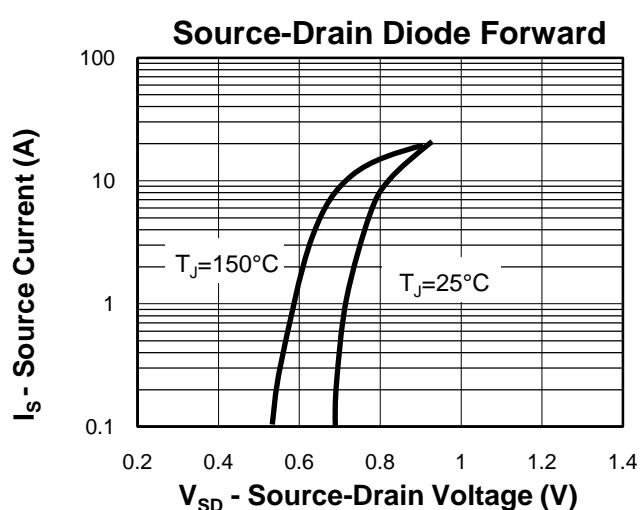
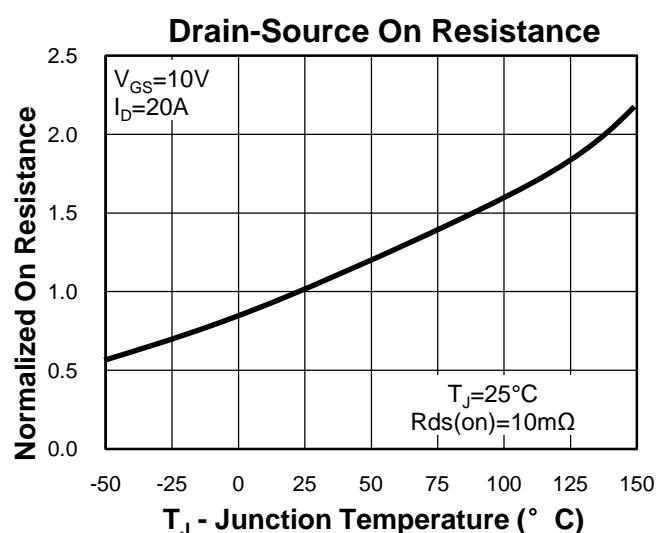
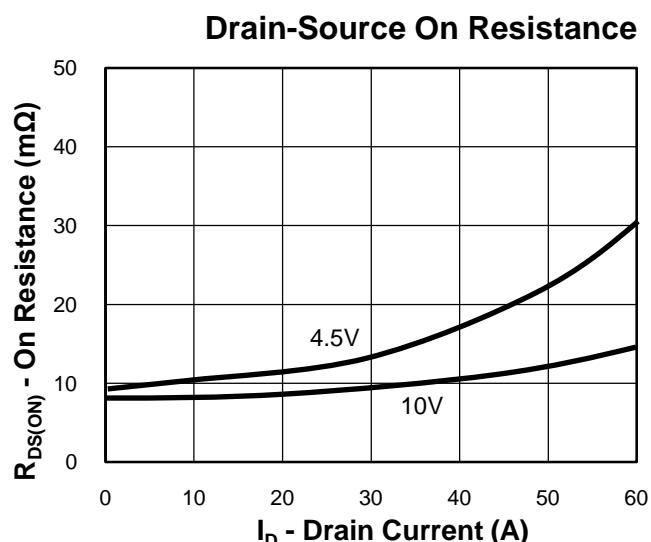
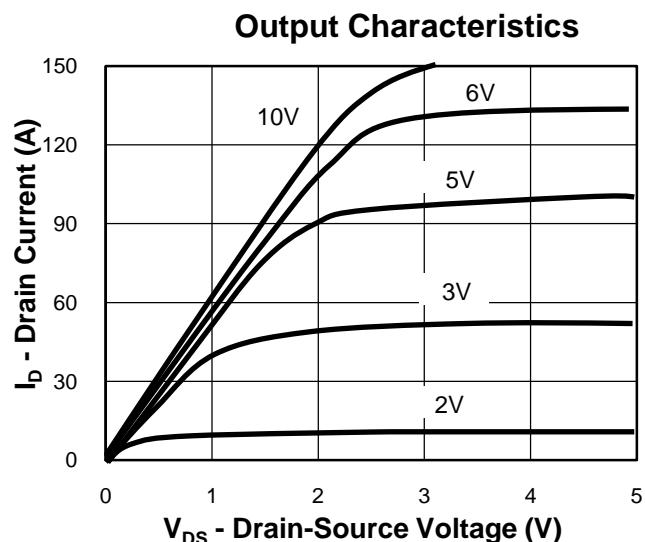
Thermal Transient Impedance



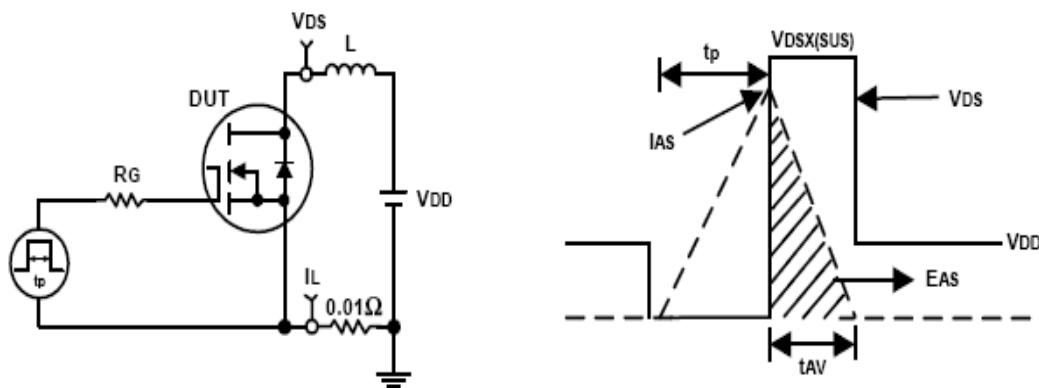
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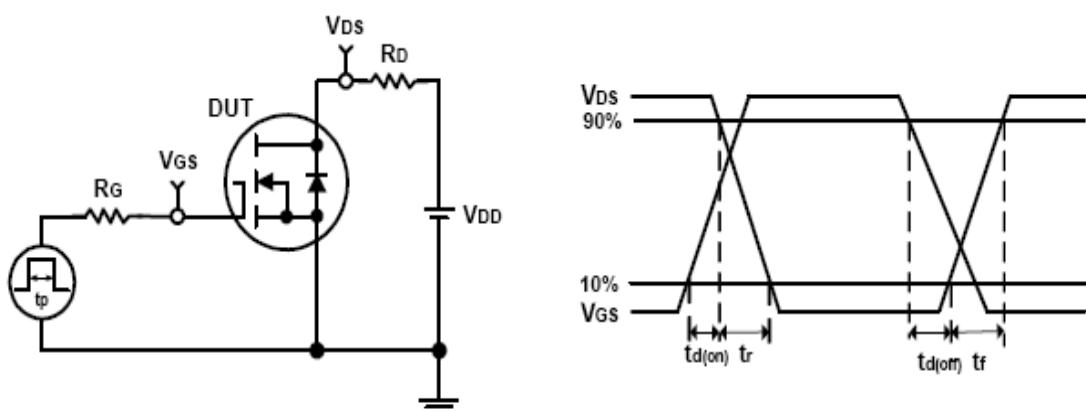
Typical Characteristics



Avalanche Test Circuit and Waveforms



Switching Time Test Circuit and Waveforms





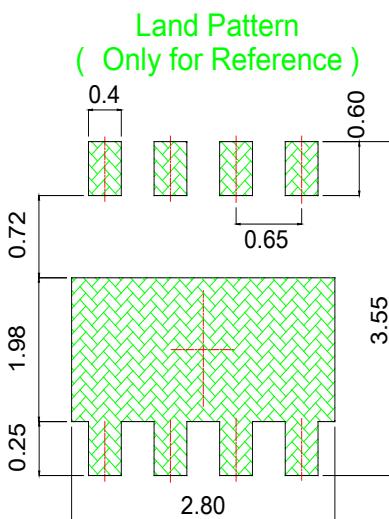
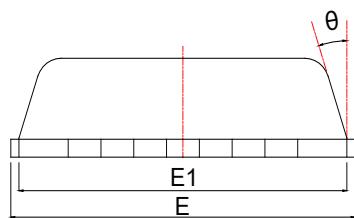
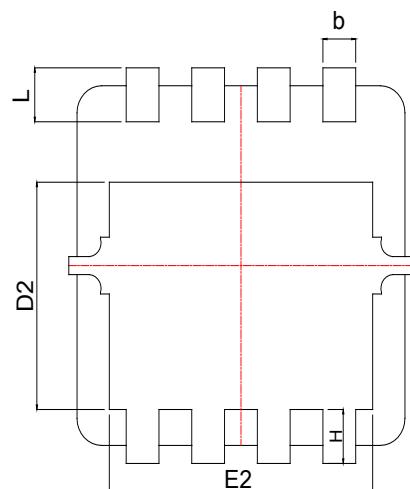
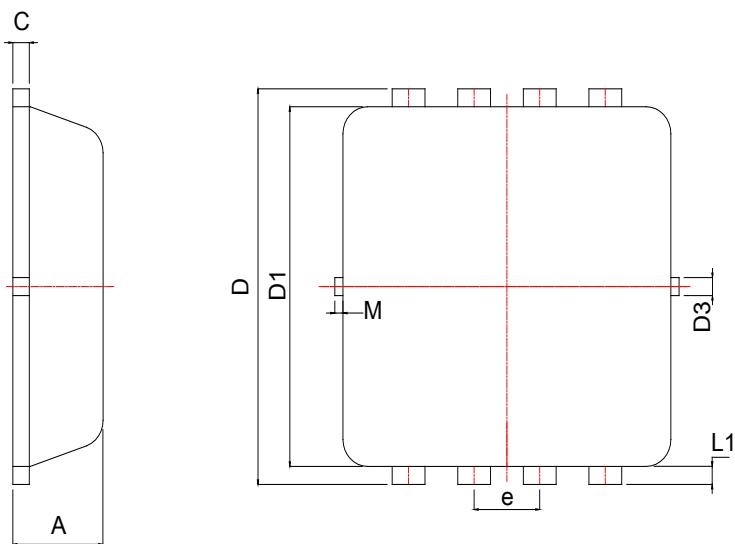
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Package Information

PDFN3333



SYMBOL	MM			INCH			SYMBOL	MM			INCH		
	MIN	NOM	MAX	MIN	NOM	MAX		MIN	NOM	MAX	MIN	NOM	MAX
A	0.70	0.75	0.80	0.028	0.030	0.031	E1	3.00	3.15	3.20	0.118	0.122	0.126
b	0.25	0.30	0.35	0.010	0.012	0.014	E2	2.39	2.49	2.59	0.094	0.098	0.102
c	0.10	0.15	0.25	0.004	0.007	0.010	e	0.65BSC			0.026BSC		
D	3.25	3.35	3.45	0.128	0.132	0.136	H	0.30	0.40	0.50	0.012	0.016	0.020
D1	3.00	3.10	3.20	0.118	0.122	0.126	L	0.30	0.40	0.50	0.012	0.016	0.020
D2	1.78	1.88	1.98	0.070	0.074	0.078	L1	*	0.13	*	*	0.005	*
D3	*	0.13	*	*	0.005	*	θ	*	10°	12°	*	10°	12°
E	3.20	3.30	3.40	0.126	0.130	0.134	M	*	*	0.15	*	*	0.006